

IGBT3 Chip

Features:

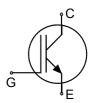
- 1200V Trench & Field Stop technology
- low turn-off losses
- short tail current
- positive temperature coefficient
- easy paralleling

This chip is used for:

power modules

Applications:

• drives



Chip Type	V _{CE}	I _C	Die Size	Package
SIGC109T120R3LE	1200V	100A	10.47 x 10.44 mm ²	sawn on foil

Mechanical Parameters

meenamearranneers				
Raster size	10.47 x 10.44			
Emitter pad size (incl. gate pad)	8 x (4.391 x 2.114)	mm ²		
Gate pad size	1.139 x 1.139	mm		
Area total	109.3			
Thickness	120	μm		
Wafer size	200	mm		
Max.possible chips per wafer	222	·		
Passivation frontside	Photoimide			
Pad metal	3200 nm AlSiCu	3200 nm AlSiCu		
Backside metal	Ni Ag –system suitable for epoxy and soft solder die	bonding		
Die bond	Electrically conductive glue or sc	Electrically conductive glue or solder		
Wire bond	AI, <500µm			
Reject ink dot size	Ø 0.65mm ; max 1.2mm	Ø 0.65mm ; max 1.2mm		
Recommended storage environment		Store in original container, in dry nitrogen, in dark environment, < 6 month at an ambient temperature of 23°C		



Maximum Ratings Symbol Parameter Value Unit Collector-Emitter voltage, Tvj =25 °C V_{CE} V 1200 1) $I_{\rm C}$ DC collector current, limited by $T_{vj max}$ А Pulsed collector current, t_p limited by $T_{vj max}$ 300 А I_{c,puls} V Gate emitter voltage $V_{\rm GE}$ ±20 °C Junction temperature range T_{vj} -55 ... +175 °C Operating junction temperature T_{vj} -55...+150 Short circuit data ²) V_{GE} = 15V, V_{CC} = 900V, T_{vj} = 125°C 10 t_{sc} μs $I_{C,max}$ = 200A, $V_{CE,max}$ = 1200V Reverse bias safe operating area²⁾ (RBSOA) $T_{\rm vj} \leq 125^{\circ} \rm C$

¹⁾ depending on thermal properties of assembly

²) not subject to production test - verified by design/characterization

Static Characteristic (tested on wafer), T_{vj} =25 °C

Parameter	Symbol	Conditions	Value			Unit
			min.	typ.	max.	
Collector-Emitter breakdown voltage	V _{(BR)CES}	V _{GE} =0V , <i>I</i> _C = 4mA	1200			
Collector-Emitter saturation voltage	V _{CEsat}	V _{GE} =15V, <i>I</i> _C =100A	1.4	1.7	2.1	V
Gate-Emitter threshold voltage	$V_{\rm GE(th)}$	$I_{\rm C}$ =4mA , $V_{\rm GE}$ = $V_{\rm CE}$	5.0	5.8	6.5	
Zero gate voltage collector current	I _{CES}	V _{CE} =1200V , V _{GE} =0V			13.4	μA
Gate-Emitter leakage current	I _{GES}	V _{CE} =0V , V _{GE} =20V			600	nA
Integrated gate resistor	r _G			7.5		Ω

Dynamic Characteristic (not subject to production test - verified by design / characterization), *T*_{vi} =25 °C

Parameter	Symbol	Conditions	Value			Unit
Falameter	Symbol		min.	typ.	max.	
Input capacitance	Cies	$V_{CE}=25V,$		7210		pF
Reverse transfer capacitance	Cres	V _{GE} =0∨, <i>f</i> =1MHz		327		



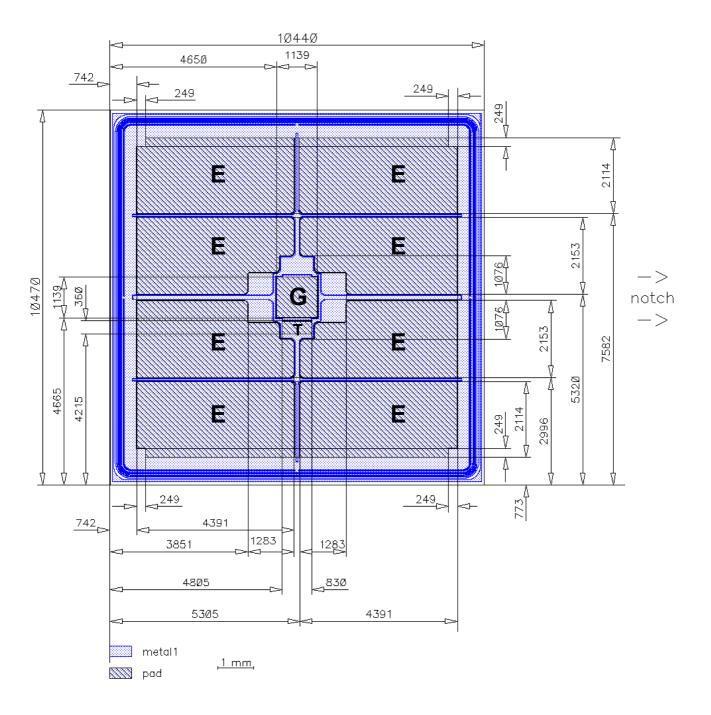
Further Electrical Characteristic

Switching characteristics and thermal properties are depending strongly on module design and mounting technology and can therefore not be specified for a bare die.



Chip Drawing

Die-Size 10440 µm x 10470 um



E = Emitter

- G = Gate
- T = Test pad do not contact



Description

AQL 0,65 for visual inspection according to failure catalogue

Electrostatic Discharge Sensitive Device according to MIL-STD 883

Revision History

Version	Subjects (major changes since last revision)	Date
2.0	Release of final datasheet, change wafer size to 200 mm	30.04.2010

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